## **REMARKS**

Claims 1-4, 6-16, 18-21 and 32-42 are now pending in the current Application. Claims 1, 13, and 15 have been amended; and claims 5, 17, and 22-31 have been cancelled. Applicants submit that the amendments do not add new matter to the current Application. All the amendments herein have been made in order to clarify the claims and not for prior art reasons. Applicants also submit that (1) no amendment made was related to the statutory requirements of patentability unless expressly stated herein, and (2) no amendment made was for the purpose of narrowing the scope of any claim, unless Applicants have argued herein that such amendment was made to distinguish over a particular reference or combination of references.

Applicants submit that claims 1 and 13 are patentable over US Patent No. 6, 551, 845 (hereinafter referred to as Moden) in view of US Patent No. 6,251,695 (hereinafter referred to as Kwon). With respect to claim 1, the Examiner has indicated that claim 5 would be allowable if rewritten in independent form; therefore, in order to further prosecution and not for prior art reasons, Applicants have amended claim 1 to include the limitations of claim 5. Claims 2-4, 6-12, and newly added claim 32 all depend directly or indirectly from allowable claim 1 and are therefore also allowable for at least those same reasons that apply to claim 1.

With respect to claim 13, Applicants have amended claim 13 to include placing the plurality of semiconductor die directly on the temporary adhesive substrate and testing in parallel at least two of the plurality of semiconductor die. Applicants submit that claim 13 is allowable over Moden in view of Kwon. For example, Applicants submit that neither Moden nor Kwon nor their combination teach or suggest testing in parallel at least two of the plurality of semiconductor die. The Examiner, in addressing claim 12 (which is also directed to testing in parallel), states that Kwon "shows that the semiconductor dies can be tested in parallel." The Examiner proceeds to state, "Note that the first die is tested before the second die." Therefore, this clearly cannot teach or suggest testing at least two die in *parallel*. Testing in parallel means testing at the same time, and if the first die is tested *before* the second die, then they are not tested *in parallel*, as claimed in claim 13. Therefore, for at least these reasons, Applicants submit that claim 13 is patentable over Moden in view of Kwon. Claims 14-16, 18-21, and newly added claims 32-36 all depend directly or indirectly from allowable claim 13 and are therefore also allowable for at least those reasons provided above with respect to claim 13.

Also, Applicants have added a new independent claim 37 which is similar to claim 1 prior to amending herein but which further characterizes the electrically isolating as using a partial saw process, as described in the specification. Neither Moden, Kwon, nor their combination teach or suggest the electrically isolating claimed in claim 37; therefore, Applicants submit that claim 37 is also allowable over Moden in view of Kwon. Claims 38-42 depend directly or indirectly from allowable claim 37 and are therefore also allowable for at least those same reasons that apply to claim 37.

## Conclusion

Although Applicants may disagree with statements made by the Examiner in reference to the claims and the cited references, Applicants are not discussing all these statements in the current Office Action, yet reserve the right to address them at a later time if necessary.

Applicants respectfully solicit allowance of the pending claims. Contact me if there are any issues regarding this communication or the current Application.

If Applicant has overlooked any additional fees, or if any overpayment has been made, the Commissioner is hereby authorized to credit or debit Deposit Account 502117.

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